

ELE 2110A Electronic Circuits

Week 10: MOS Logic Circuits

(45 minutes only)



Topics to cover ...

- CMOS Inverter
 - Static characteristics
 - Dynamic characteristics
 - Power dissipation
- Other CMOS logic gates

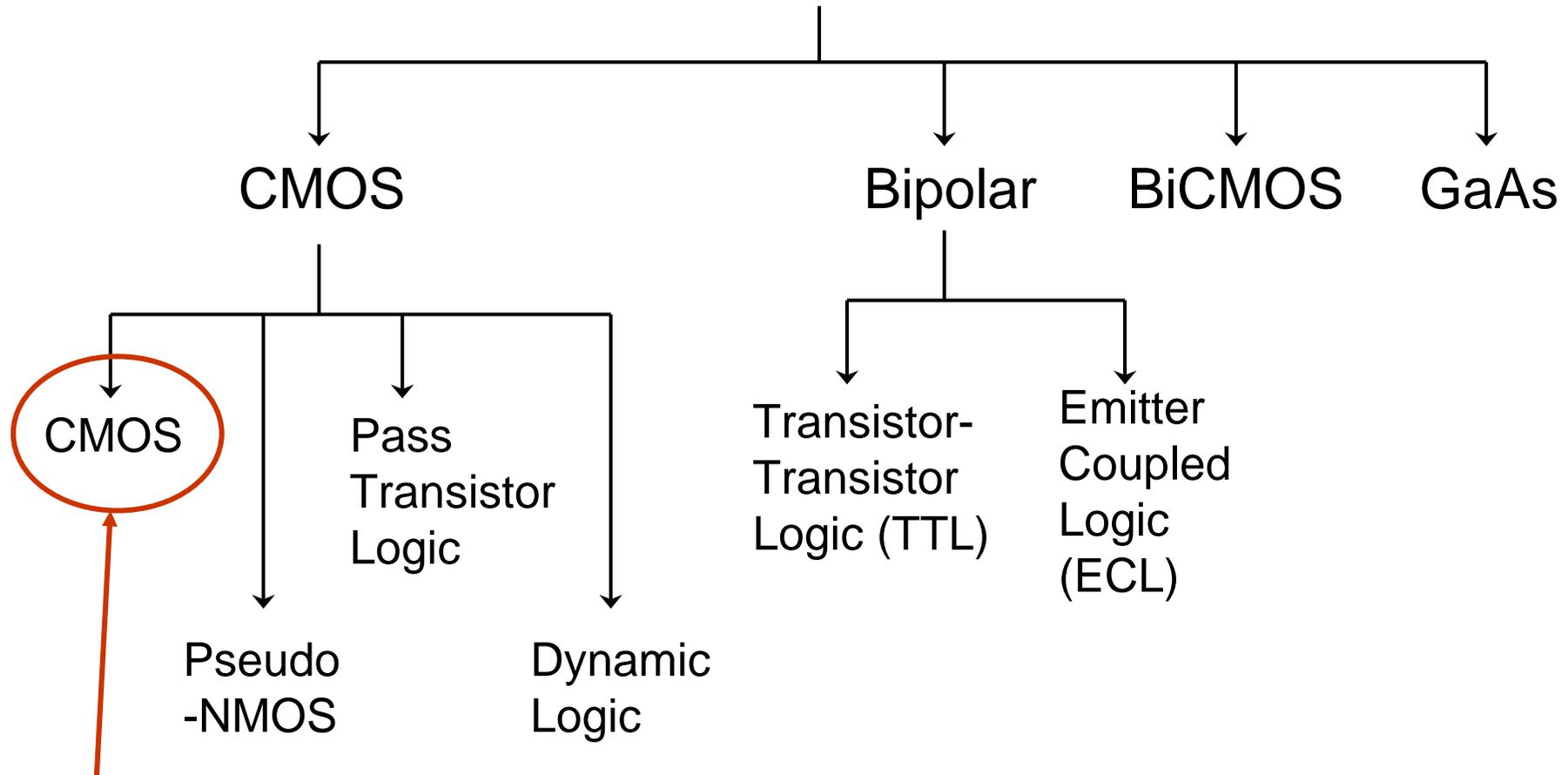
Reading Assignment:

Chap 6.1-6.3, 7.1-7.4 of Jaeger and Blalock or
Chap 7.1 - 7.3, 7.7 of Sedra and Smith



Digital IC Technologies and Logic-Circuit Family

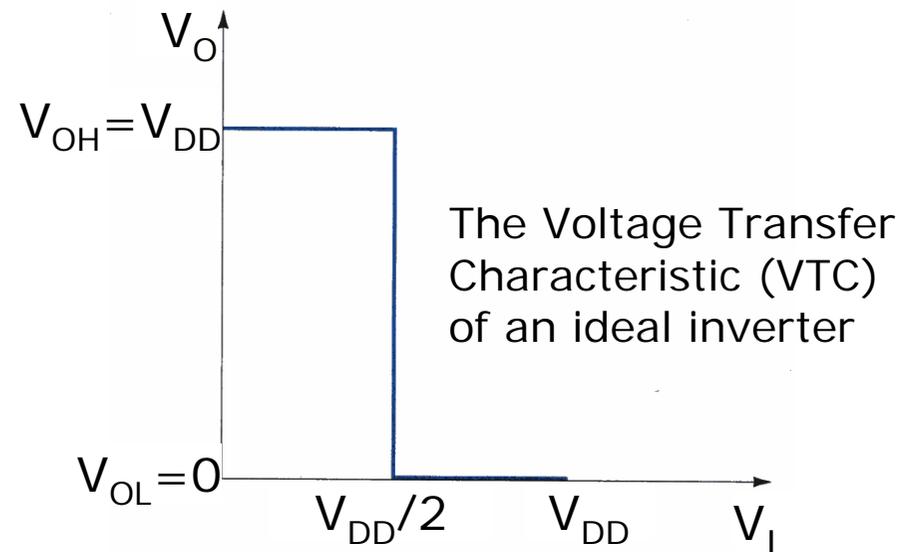
Digital IC technologies & logic circuit family



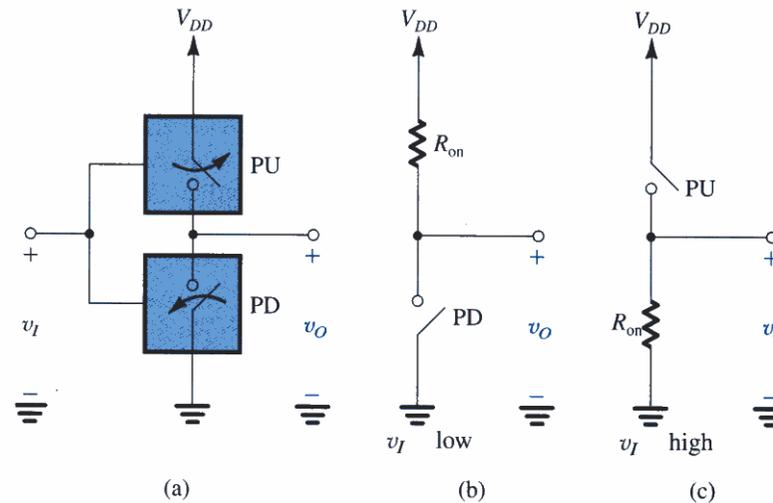
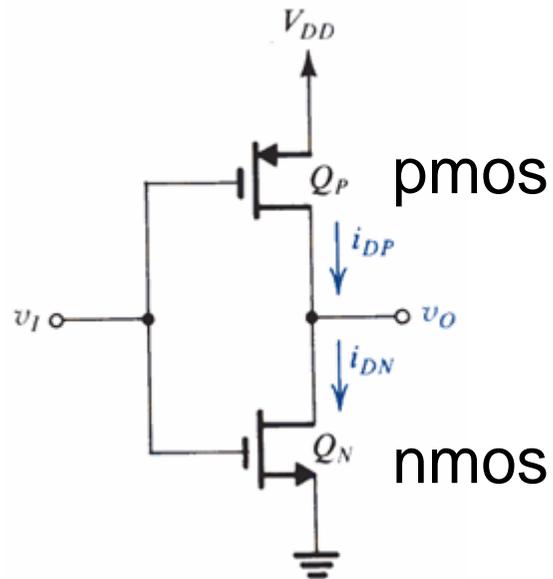
This course



Ideal Inverter



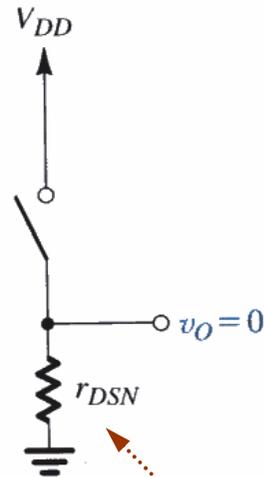
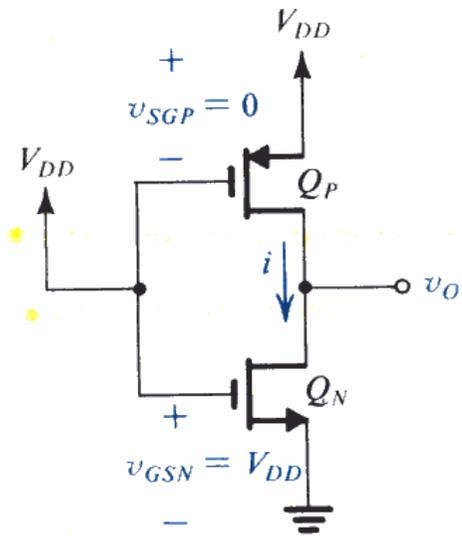
CMOS Inverter



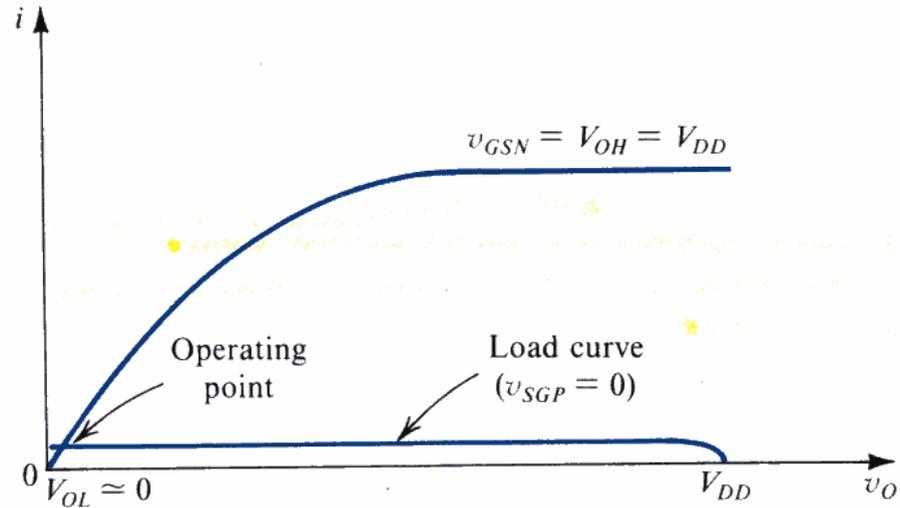
PU: pull up network, responsible for producing HIGH output
PD: pull down network, responsible for producing LOW output



Case 1: $V_I = V_{DD}$



"pull-down"



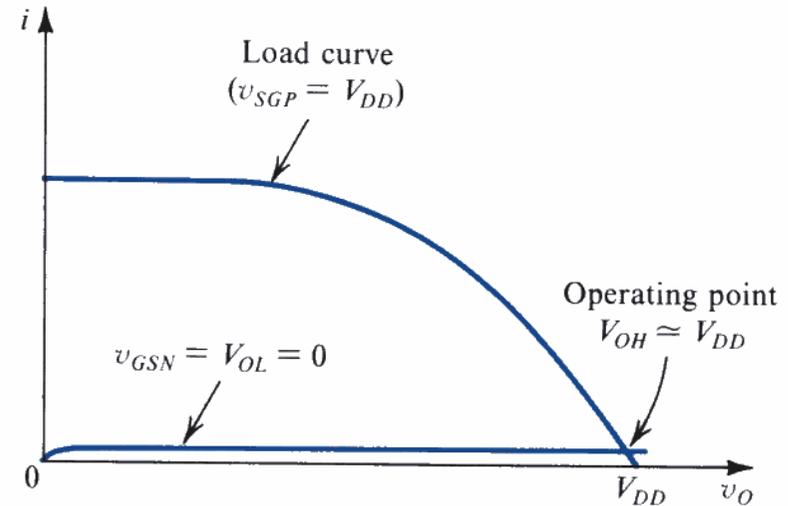
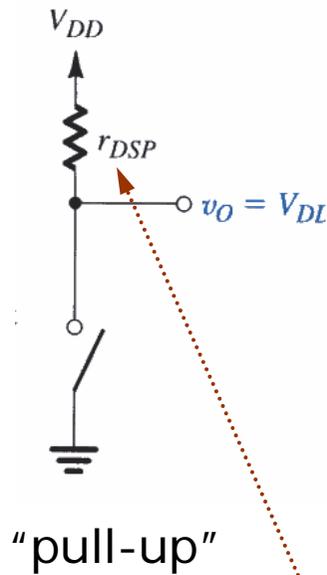
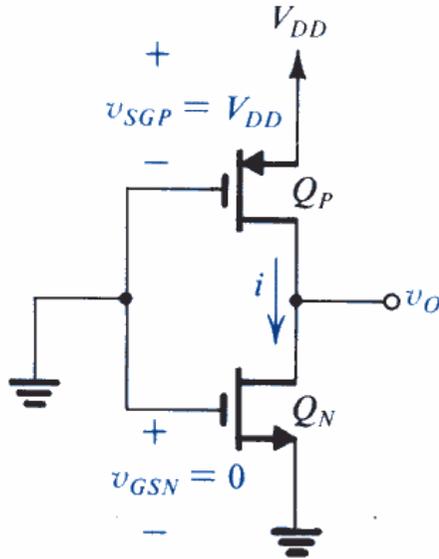
Q_P OFF
 Q_N ON: output pulled down
 $\rightarrow V_O = 0V$

The output resistance of Q_N
 (linear mode):

$$r_{DSN} = \frac{1}{k'_n \left(\frac{W}{L} \right) (V_{DD} - V_{tn})}$$



Case 2: $V_I = 0V$



Q_N OFF
 Q_P ON: output pulled up.
 $\rightarrow V_O = V_{DD}$

The output resistance of Q_P (linear mode):

$$r_{DSN} = \frac{1}{k'_p \left(\frac{W}{L} \right) (V_{DD} - V_{tp})}$$



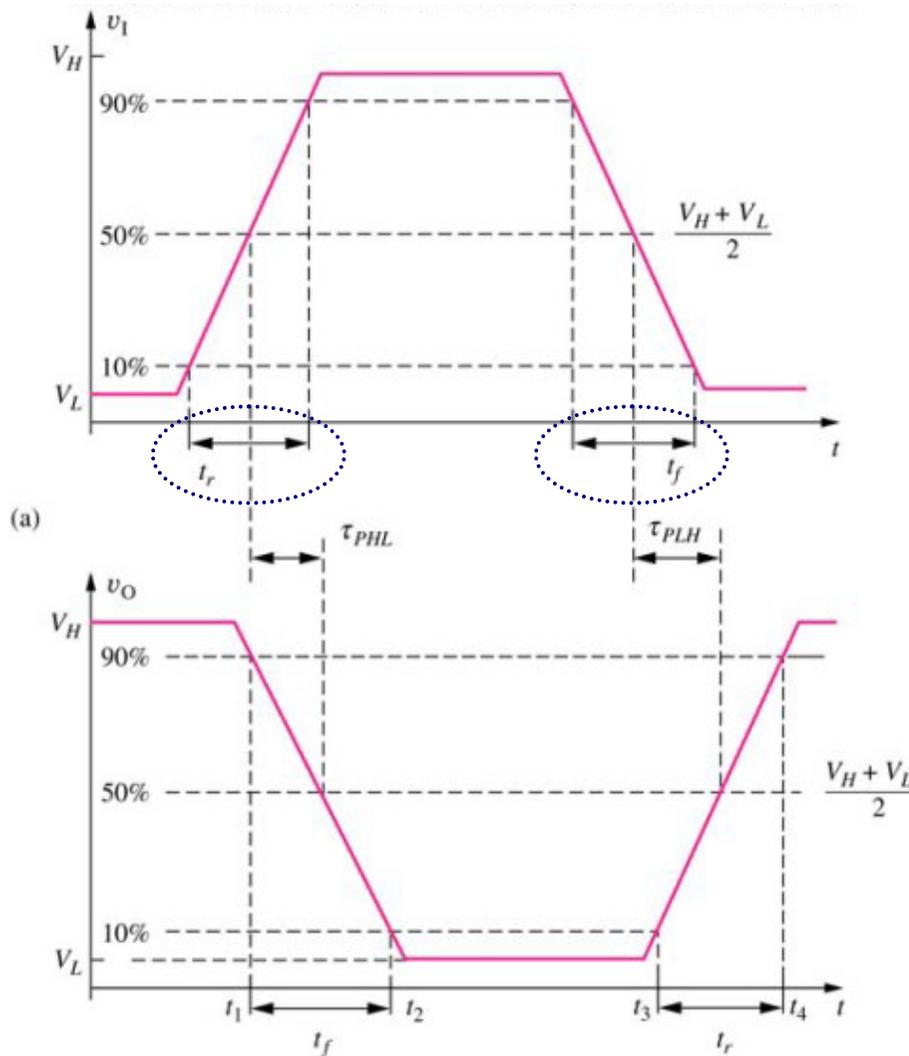
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Dynamic Characteristic: Rise and Fall times

- The rise and fall times, t_f and t_r , are measured at the 10% and 90% points on the transitions between the two states.



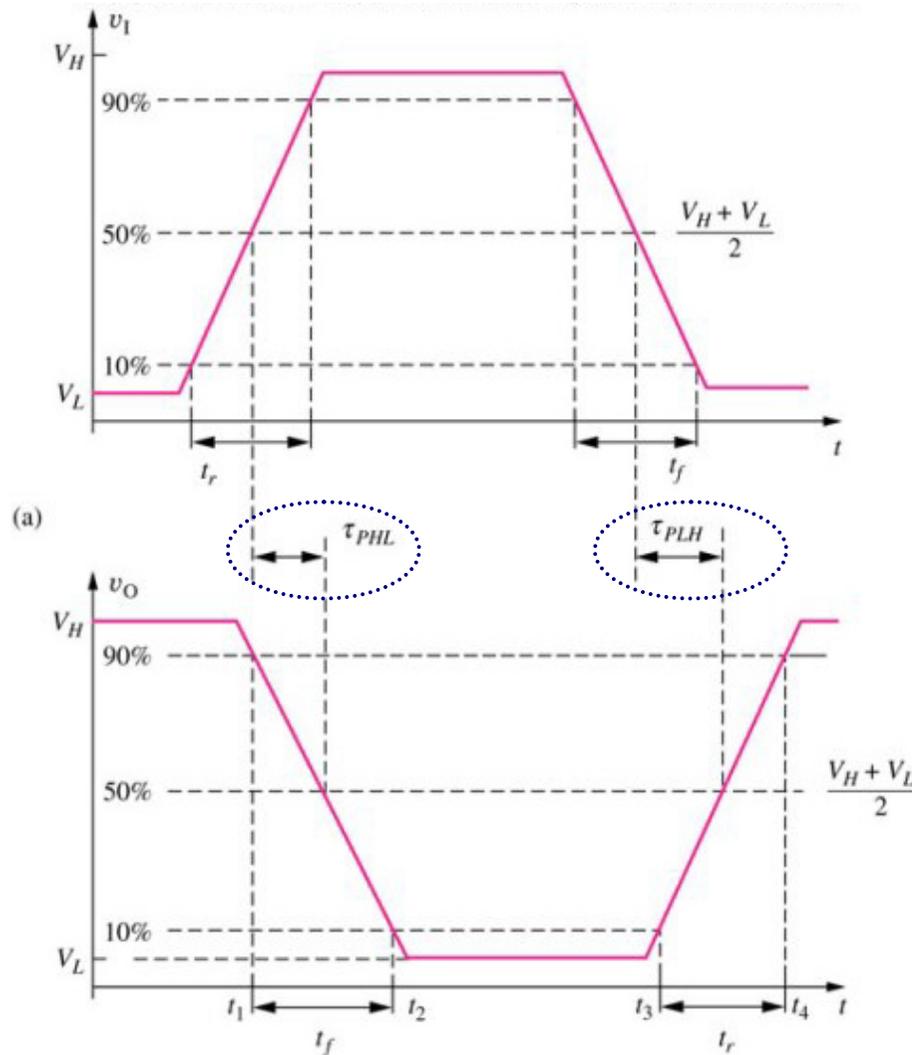
$$V_{10\%} = V_L + 0.1\Delta V$$

$$V_{90\%} = V_L + 0.9\Delta V$$

$$= V_H - 0.1\Delta V$$



Dynamic Characteristic: Propagation Delay

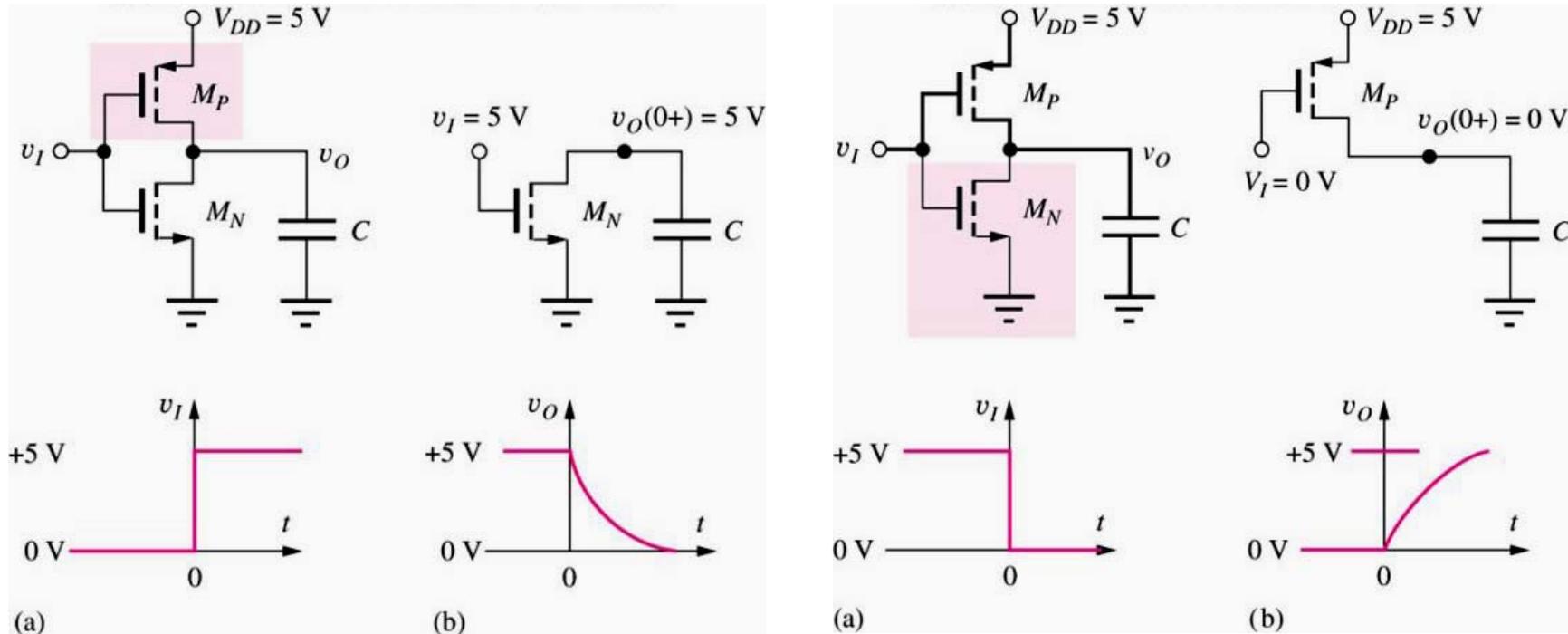


- Propagation delay: the time between a change at the 50% point input to cause a change at the 50% point of the output
- The high-to-low prop delay, τ_{PHL} , and the low-to-high prop delay, τ_{PLH} , are usually not equal, but can be described as an average value:

$$\tau_P = \frac{\tau_{PHL} + \tau_{PLH}}{2}$$



Propagation Delay



- C represents parasitic capacitances:
 - MOS gate capacitance of next logic gate
 - Wire capacitance to ground
- Output parasitic capacitor voltage cannot change instantaneously
- Capacitive charging/discharging contributes to propagation delay



Propagation Delay Estimate

- It can be shown (see section 7.3.1 and 6.14.12)

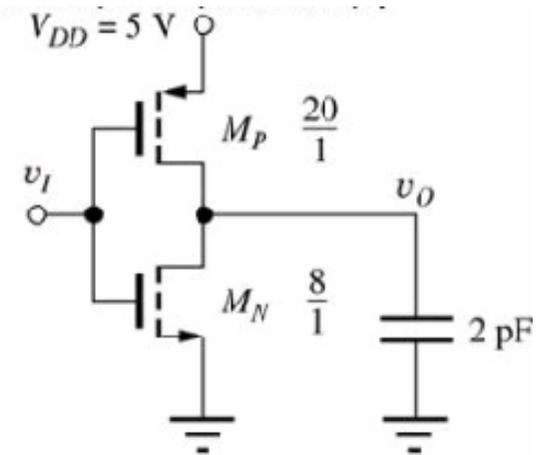
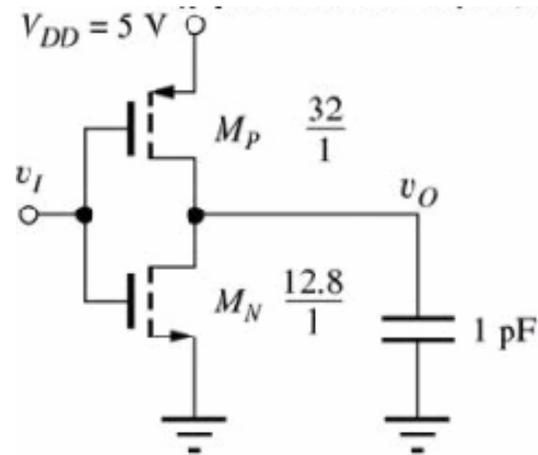
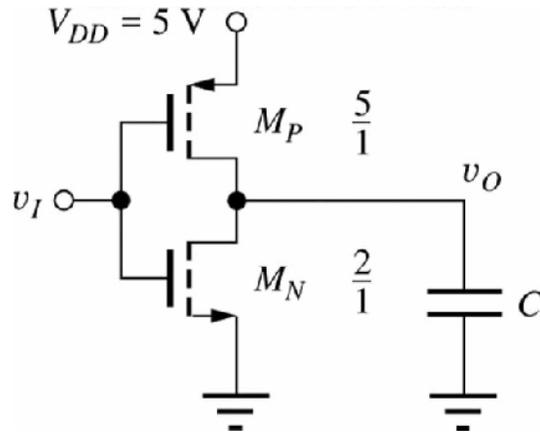
$$\tau_{PHL} \propto R_{onN} C$$

$$\text{where } R_{onN} = \frac{1}{\mu_n C_{ox} \frac{W}{L} (V_H - V_{TN})}$$

- For matched nmos and pmos ($\mu_n C_{ox} \left(\frac{W}{L}\right)_n = \mu_p C_{ox} \left(\frac{W}{L}\right)_p$), $\tau_{PLH} = \tau_{PHL}$
- The delay depends on C
 - In smaller feature size CMOS process, wires and transistors are smaller
 - Parasitic C is smaller
 - Delay is smaller → Circuits run faster
- The delay also depends on R_{ON}



Example



Given that:

For $C=1\text{ pF}$,

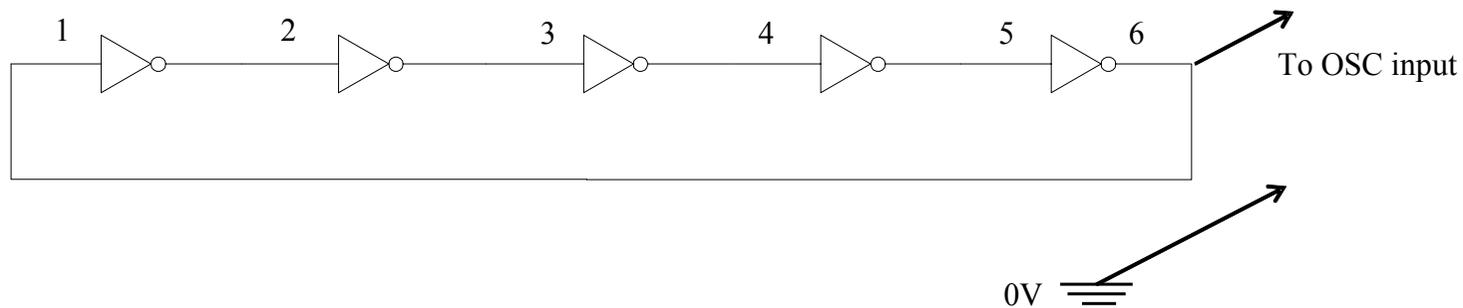
$$\tau_p = 6.4\text{ ns}$$

$$\tau_p = ?$$

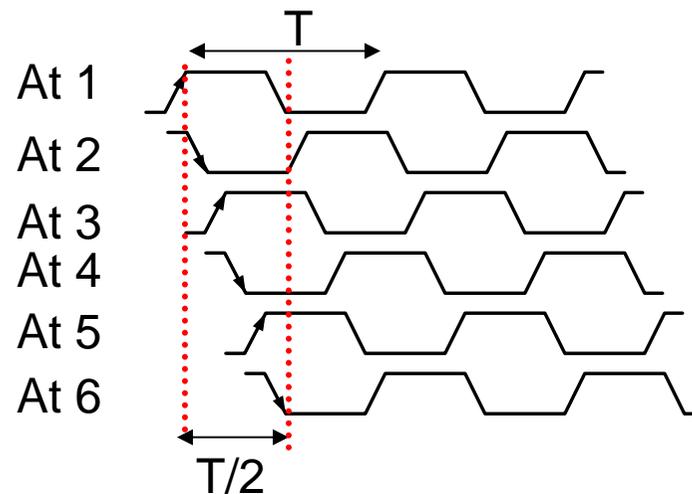
$$\tau_p = ?$$



Ring Oscillator



- If odd number of inverters (at least 3) are connected as a ring, it oscillates.
- Oscillation frequency relates to the propagation delay of the inverters
- Waveform at 6 = waveform at 1 \rightarrow 5 Delays = $T/2$ \rightarrow Delay = $T/10$



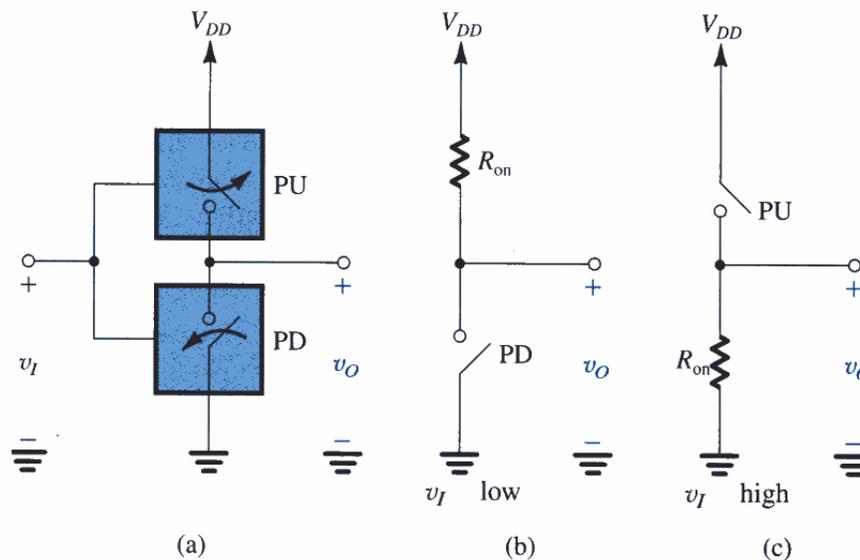
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Power Dissipation

- CMOS logic has no static power dissipation
 - There is no DC path between V_{DD} and GND at any time

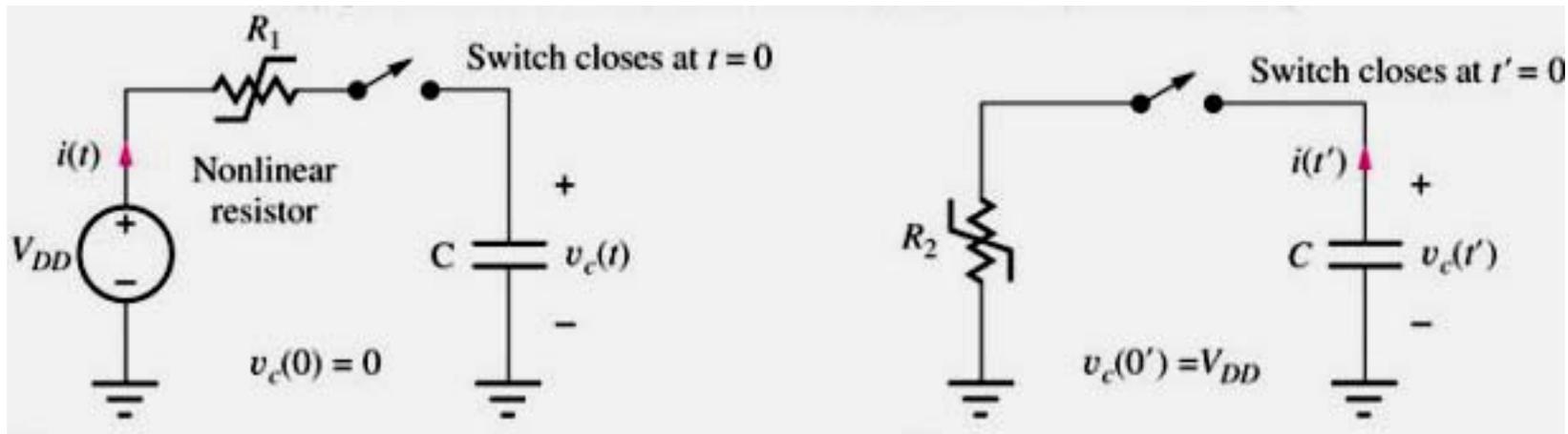


- But, when the inverter changes its output...



Dynamic Power Dissipation

- When the inverter charges or discharges the output capacitor, it consumes power.



Charging

Discharging



Dynamic Power Dissipation

- The energy delivered from the VDD is:

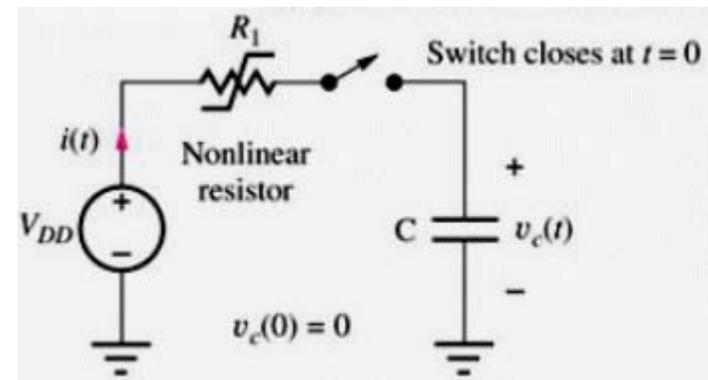
$$E_D = V_{DD} \int_0^{\infty} i(t) dt = V_{DD} \int_0^{\infty} \frac{dq(t)}{dt} dt = CV_{DD} \int_{V_C(0)}^{V_C(\infty)} 1 dv_C = CV_{DD}^2$$

- The energy stored by the capacitor is:

$$E_S = \frac{CV_{DD}^2}{2}$$

- The difference between the above two terms represents the energy lost in the resistive elements:

$$E_L = E_D - E_S = \frac{CV_{DD}^2}{2}$$



Dynamic Power Dissipation

- The total energy lost in the first charging and discharging of the capacitor through resistive elements is given by:

$$E_{TD} = \frac{CV_{DD}^2}{2} + \frac{CV_{DD}^2}{2} = CV_{DD}^2$$

- For every clock cycle, the dynamic power dissipation is:

$$P_D = \text{Energy/Time} = CV_{DD}^2 f$$

- This result can be extended to a complex digital IC, where C represents the area of the IC
- Lower V_{DD} is very effective for reducing power supply
- Reducing C also helps reducing power



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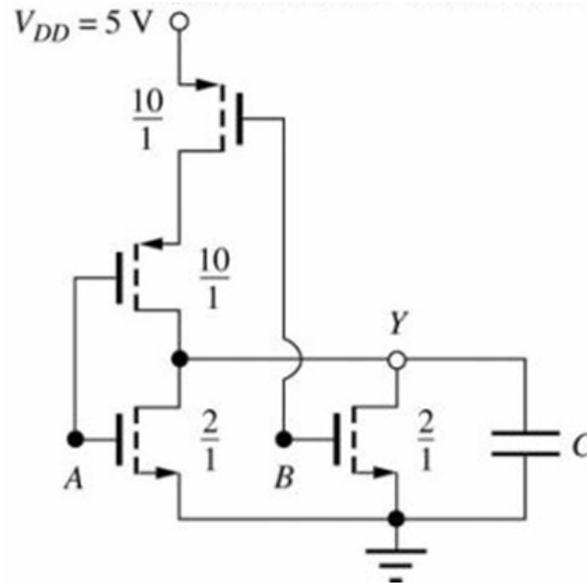
CMOS NOR Gate

Pull-up Network:

$$Y = \overline{A} \overline{B}$$

Pull-down Network:

$$\overline{Y} = A + B$$



$$Y = \overline{A + B}$$

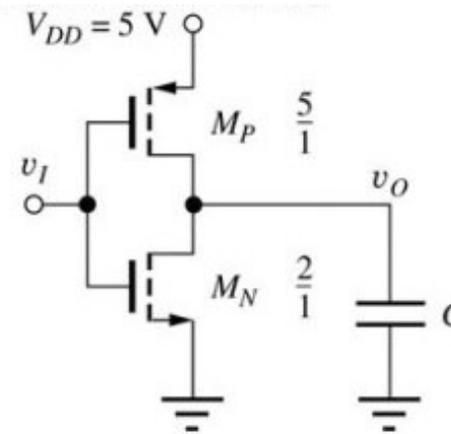
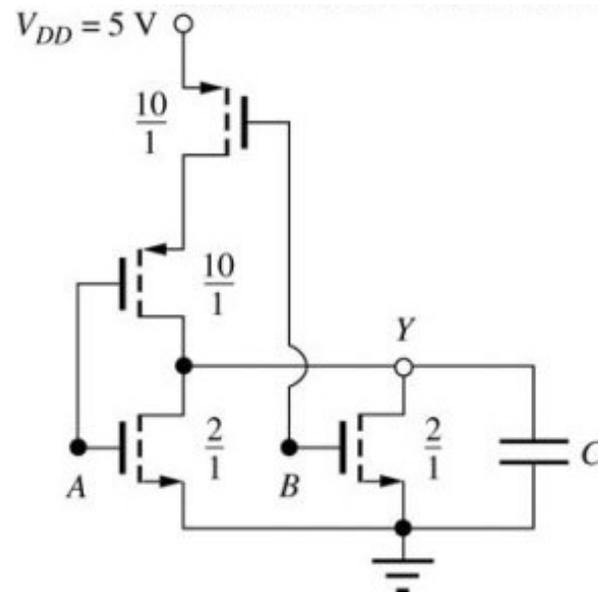
TABLE 7.3
CMOS NOR Gate Truth Table and Transistor States

A	B	$Y = \overline{A + B}$	NMOS-A	NMOS-B	PMOS-A	PMOS-B
0	0	1	Off	Off	On	On
0	1	0	Off	On	On	Off
1	0	0	On	Off	Off	On
1	1	0	On	On	Off	Off



Gate Sizing

- Want to keep the delay times the same as a reference inverter under the worst case input conditions.
- Consider a two-input NOR gate:
 - $(W/L)_n$ should be same as that of the inverter
 - $(W/L)_p$ should be twice as large as that of the inverter



Reference Inverter



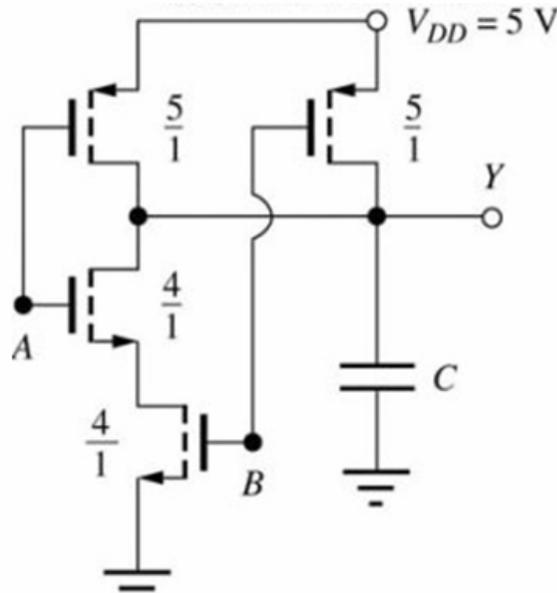
CMOS NAND Gate

Pull-up Network:

$$Y = \overline{A} + \overline{B}$$

Pull-down Network:

$$\overline{Y} = AB$$



$$Y = \overline{AB}$$

TABLE 7.5

CMOS NAND Gate Truth Table and Transistor States

A	B	$Y = \overline{AB}$	NMOS-A	NMOS-B	PMOS-A	PMOS-B
0	0	1	Off	Off	On	On
0	1	1	Off	On	On	Off
1	0	1	On	Off	Off	On
1	1	0	On	On	Off	Off

